## Notice of References Cited Application/Control No. 10/593,864 Examiner Gene W. Lee Applicant(s)/Patent Under Reexamination MAEDE ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,961,009 A	10-1990	Baik, Woo H.	327/103
*	В	US-6,317,138 B1	11-2001	Yano et al.	345/589
*	С	US-2003/0052904 A1	03-2003	Gu, Gong	345/691
*	D	US-2004/0174388 A1	09-2004	Sempel et al.	345/691
*	Е	US-2005/0184933 A1	08-2005	Tomohara, Kiyohide	345/076
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	7	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	>						
	w						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.